

ANALYTICAL PROBER

ASPECT L1



THE DESIGN

VERSATILE AND COST-EFFECTIVE PROBING

The Aspect L1 manual analytical wafer prober offers a versatile and cost effective solution for general diagnostic probing, engineering test and failure analysis of microcircuits on wafer substrates up to 200mm (8"). It offers users the advantage of an economical manual prober with the ability to significantly enhance its performance.

FLEXIBLE DESIGN

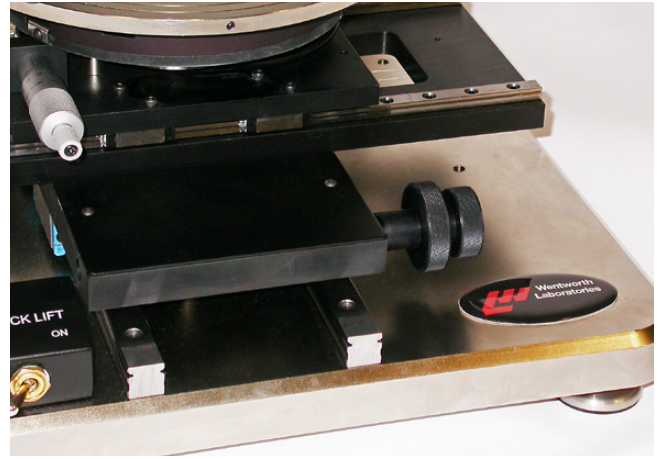
The Aspect L1 wafer prober is rigidly constructed and its compact platform is easily accessible and upgradeable. Fast probe mode is available in addition to either a high power or low power optics package. It is designed to accept thermal chucks, and can simultaneously accommodate Wentworth PVX 400 manipulators and a probe card holder for Wentworth cantilever probe cards.

KEY FEATURES

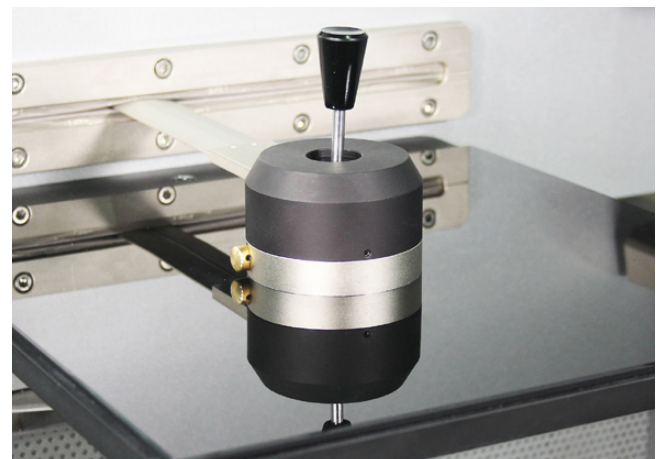
- ✓ Up to 200 mm (8") wafer capability
- ✓ Rigid construction
- ✓ Precision manual XY stage and theta rotation
- ✓ Chuck plate vacuum lift
- ✓ Manual fine and coarse platform height adjustment

OPTIONS

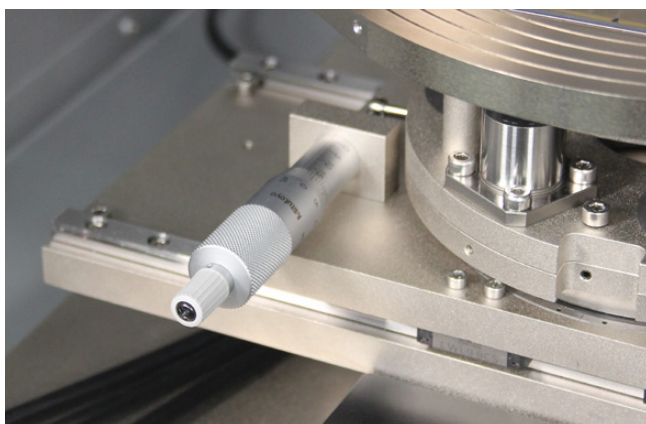
- ✓ Extensive range of probing accessories and cantilever probe cards available
- ✓ High and low power optics
- ✓ Fast probe mode
- ✓ Probe card holder
- ✓ Pantograph stage movement available



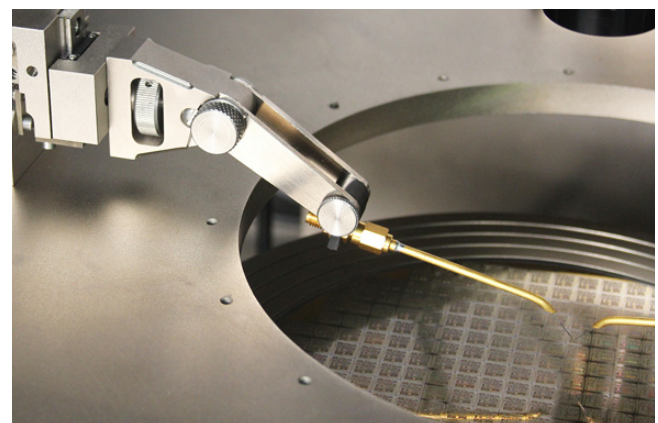
XY stage controls



Joystick for fine positioning



Chuck plate with theta adjuster



PVX 400 Micromanipulator

SPECIFICATIONS

ASPECT L1 MANUAL ANALYTICAL 200 MM PROBER

Platform
Electroless nickel-plated
5 mm coarse lift, hand operated
0-25 mm micrometer height adjustment
Stage
Manually driven by two coaxially mounted knobs. Where a local enclosure is required around Aspect L1, the fast probe option provides a means of moving the XY stage externally.
Travel XY = 200 mm (8.0 x 8.0")
Fine theta rotation ($\pm 7^\circ$)
Wafer Chuck
Vacuum hold down on wafer
0.25 mm fine lift by vacuum
Microscope Mount
Stereo zoom microscopes with forward and backward travel and 180° swing option. Rigid bridge mount for high magnification optics option—independent of platform—to ensure probing integrity as microscope is moved, accommodates manual or driven XYZ mounts.
Probe Card Holder
114 mm to 150 mm (4.5 to 6.0")
Accessories
Consult factory for details
Dimensions
Width 380 mm
Depth 555 mm
Height 210 mm
Weight 27 kg
Services
Vacuum 0.5 cfm @ 20"Hg (min)

ABOUT WENTWORTH LABORATORIES

With over 50 years experience in wafer probing technology, our solutions are the number one choice for many leading-edge wafer test applications across the globe.

With the support of a world-wide network of representatives, we enable our customers to fulfil even the most challenging wafer probing goals, maximizing their productivity and reducing costs.

We look forward to discussing your wafer probing requirements.

Wentworth Laboratories Ltd

1 Gosforth Close, Sandy
Bedfordshire, SG19 1RB
United Kingdom

Tel: +44 1767 681221

Email: info@wentworthlabs.com

Wentworth Laboratories, Inc

1087 Federal Road, Unit 4
Brookfield, Connecticut 06804
United States

Tel: +1 203 775 0448

Email: info@wentworthlabs.com



v 08/19